

Radial electron fluence around ion tracks as a new physical parameter for the detection threshold of PADC using Geant4-DNA toolkit



Tamon Kusumoto^{a,b,f}, Ziad EL Bitar^b, Shogo Okada^c, Pierre Gillet^b, Nicolas Arbor^b, Masato Kanasaki^a, Yutaka Mori^a, Keiji Oda^a, Abdel-Mjid Nourreddine^b, Hisaya Kurashige^c, Michel Fromm^d, Pierre Cloutier^e, Andrew D. Bass^e, Léon Sanche^e, Satoshi Kodaira^f, Rémi Barillon^b, Tomoya Yamauchi^{a,*}

^a Graduate School of Maritime Sciences, Kobe University, 5-1-1 Fukaeminami-machi, Higashinada-ku, 658-0022, Kobe, Japan

^b Institut Pluridisciplinaire Hubert Curien (IPHC), Université de Strasbourg, 23 rue du Loess, 67037, Strasbourg Cedex, France

^c Organization for Advanced and Integrated Research, Kobe University, 1-1 Rokkodai, Nada-ku, 657-8501, Kobe, Japan

^d Université de Bourgogne-France-Comté, 16 Route de Gray, F-2530, Besançon Cedex, France

^e Faculté de Médecine, Université de Sherbrooke, Sherbrooke, J1H 5N4, Canada

^f Radiation Measurement Research Team, National Institute of Radiological Sciences, National Institutes for Quantum and Radiological Science and Technology, 4-9-1 Anagawa, Inage-ku, 263-8555, Chiba, Japan

ARTICLE INFO

Keywords:

Geant4-DNA

PADC

Detection threshold

Latent track

REFIT

ABSTRACT

The detection threshold of poly(allyl diglycol carbonate), PADC, for C ions is determined as 55 eV/nm in stopping power, which is significantly higher than that for proton and He ions. The stopping power is not a universal parameter for expressing the detection threshold of PADC. A new physical parameter of Radial Electron Fluence around Ion Tracks, *REFIT*, is proposed to describe the detection threshold of PADC. It is defined as the number density of electrons passing through the surface of a cylinder of a certain radius that is co-axial with the trajectory. Furthermore, preliminary calculations are presently being performed using the Monte Carlo simulation code of Geant4-DNA. The values of the *REFIT* at the detection thresholds for each ion are of the same order. Several issues affecting implementation of the *REFIT* parameter are discussed. These include the effects of impact parameter relating to the initial locations of secondary electrons, the effects of electron attachment below the cut off energy of 7.4 eV and the necessity of a more physically realistic medium than water for Monte Carlo simulations.

1. Introduction

Poly allyl(diglycol carbonate), PADC, has been considered the most sensitive etched track detector and is widely known by the trade name of CR-39 (Cartwright et al., 1978). When it is irradiated with protons or heavy ions, permanent damage in the form of latent tracks are generated along each ion path. After chemical etching, latent tracks are, above the detection threshold, observable with optical microscopes as etch pits (Somogyi et al., 1976). The track registration sensitivity, S , is defined as $S = V - I$, where V is the ratio of track etching velocity V_t to the bulk etching velocity V_b ($V \equiv V_t/V_b$). Assuming normal incidence and that V_t is constant with the etching depth, S has been derived as follows:

$$S = \frac{1 + (r/G)^2}{1 - (r/G)^2} - 1, \quad (1)$$

where r is the etch pit radius (in μm) and G is the thickness layer removed (in μm). Fig. 1 shows a repeat unit of PADC which is composed of a radio-sensitive and radio-tolerant sections. The radio-sensitive section comprises an ether and carbonate esters connected by ethylene groups. The radio-tolerant part is the “polyethylene-like” network formed during the polymerization. The length of a repeat unit of PADC is about 2 nm. We have conducted a series of FT-IR spectrometric studies to understand the latent track structure of protons and heavy ions in PADC (Yamauchi, 2003; Mori et al., 2011; Kusumoto et al., 2016a). We demonstrated that at least two electrons are necessary to break the carbonate ester. Additionally, more than two radio-sensitive parts must be lost in track's radial direction, for the latent track be etchable (Kusumoto et al., 2016b). These results indicated that the number of electrons which pass through each single repeat unit is the critical factor in elucidating the difference between etchable tracks and un-

* Corresponding author.

E-mail address: yamauchi@tiger.kobe-u.ac.jp (T. Yamauchi).

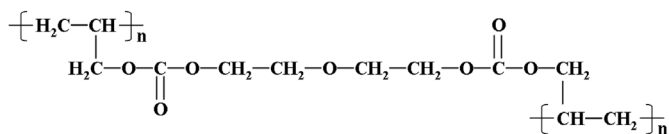


Fig. 1. A repeat unit of PADC.

etchable ones. In this study, we simulate the 3-D spatial distribution of secondary electrons around tracks of protons, He and C ions in the virtual PADC and obtain the number density of electrons as a function of the radial distance from the ion trajectory using the Geant4-DNA toolkit.

2. Simulation code and experiments

A Monte Carlo simulation in the Geant4-DNA toolkit was performed to investigate the number of secondary electrons around ion tracks (Allison et al., 2006 & 2016; Agostinelli et al., 2003). We used the “G4EmDNAPhysics” physics constructor installed in Geant4-DNA ver. 10.3.p01, in which the discrete processes including ionization, electronic excitation, vibrational excitation, elastic scattering and molecular attachment for electron was taken into account, for energies down to 7.4 eV. Furthermore, the ionization processes of heavy ions up to Fe^{26+} can be included (Incerti et al., 2014). In this study, rather than PADC, the target is set as a virtual stopping medium having the same chemical composition as water but a density of 1.31 g/cm^3 , which is equivalent to that of PADC.

Commercially obtained PADC sheets of BARYOTRAK with a nominal thickness of 0.9 mm (Fukui Chemical Industry Co., Ltd., Japan), which were made from purified monomers were used to determine the detection threshold for etch pit formation. The PADC sheets were made as the stack during exposures to C ions with an incident energy of 135 MeV/u in ambient air at the biological irradiation room of the Heavy Ion Medical Accelerator, HIMAC, Chiba equipped in National Institute of Radiological Sciences, NIRS, in Japan. C ions were completely stopped within the PADC stack. We conducted etching tests for 4 h in 6 M KOH solution kept at 70°C after the irradiations. The size of etch pit openings was measured by optical microscope (BX60-F3, OLYMPUS, Japan) operated by WinROOF ver. 5.04 imaging processor (MITANI Corporation, Japan).

3. Results and discussion

3.1. Detection thresholds of PADC

Fig. 2(a) shows the track response of PADC to C ions as a function of the stopping power, as well as previously reported data for proton and He ion irradiations (Hassan et al., 2013). We have defined the detection threshold as the original point at which the evolution of etch pits starts along the latent track under the surface, when the chemical etching was progressing from the front surface each heavy ions entered (Yamauchi et al., 2017). In normal incidence, the threshold can be attained by extrapolating the fitted growth curves of each etch pit to zero radius. The thresholds are also expressed by the stopping power at the original points (Ziegler, 2004). The detection threshold for C ions is 55 eV/nm, which is greater than those of protons (17 eV/nm) and He ions (37 eV/nm) as indicated by arrows in Fig. 2(a). As shown in Fig. 2(a), the stopping power is not a universal parameter for expressing the sensitivity and the detection threshold. The Restricted Energy Loss, *REL*, in which the high energy components of secondary electrons has been assumed not to contribute to the track formation has been developed as a suitable parameter for track registration in polymeric detectors (Benton&Nix, 1969). For the cut-off energy, ω_0 , of secondary electrons, a value of 200 eV has been used for PADC (Kodaira et al., 2013). The sensitivities of proton, He and C ions at each detection threshold are

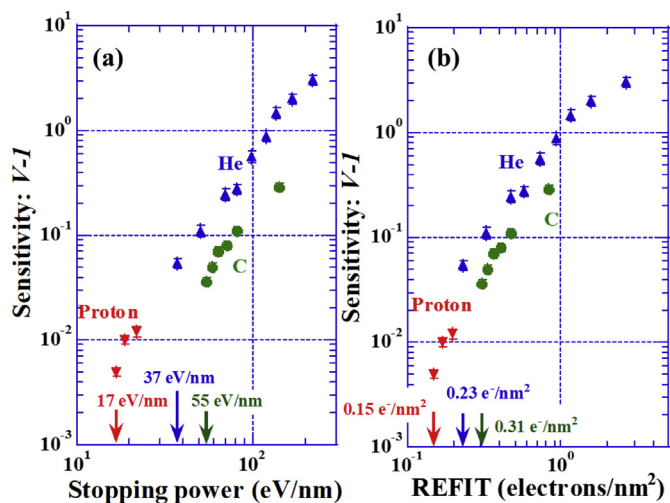


Fig. 2. Track response data as a function of the stopping power (a) and the *REFIT* at a radius of 1 nm (b). The arrows indicate the detection thresholds for each ion. The error bars indicate each standard deviation.

different from each other. This suggests that it is impossible to describe the detection thresholds by a single value of *REL*. The radial dose distribution theory has also been used as a universal parameter for expressing the track etchability of LiF crystals irradiated with GeV ions (Schwartz et al., 1998). This theory however could not simply applied to express the latent track structure in PADC (Barillon et al., 2015).

3.2. A new physical concept for the detection thresholds of PADC

In PADC, at least two electrons are required to break the carbonate ester (Kusumoto et al., 2016a) and more than two radio-sensitive parts must be lost in the track's radial direction for tracks to be etchable (Kusumoto et al., 2016b). Based on these experimental results, we focus on the most fundamental variable (i.e. number density of secondary electrons around ion trajectories) and propose the Radial Electron Fluence around Ion Tracks, *REFIT*, as a new physical parameter to express the detection threshold of PADC. *REFIT* is defined as the number density of secondary electrons that traverse a cylindrical surface coaxial with the ion trajectory. In general, fluence is defined as the number of particles incident on a sphere divided by the cross-sectional area of the sphere. In the present case, we count the electrons passing through the surface of a cylinder of a certain radius, because spatially, the tracks of secondary electrons are of cylindrical symmetry around the ion path. The inset sketch in Fig. 3 shows a simulation result for the electron tracks produced by C ions with an incident energy of 51 MeV/u whose trajectory is illustrated by the blue line. The secondary electron tracks are indicated as the red lines. The yellow points show the interaction points. The secondary electrons are assumed to originate from each point on the ion trajectory. The secondary electrons produce many further electrons before terminating their trajectory at some radius and individual history which depend on the initial energy of electrons. These further electrons are also calculated. We set-up a series of cylinders, with radius increasing in steps of 0.1 nm, and evaluated the number of electrons that crossed the sides of each cylinder in the both directions, forwards and backs. Fig. 3 indicates the *REFIT* for proton, He and C ions, which are calculated at the detection thresholds for each ion, as a function of the distance from ion's path. The values of *REFIT* decrease with increasing radius, and heavier ions have larger values. Unfortunately, we do not find a common value of *REFIT* at any radius. However, the values of *REFIT* at a radius of 1 nm, which is the half of the length of a repeat unit of PADC, are in agreement with a Multi-hit model that was experimentally obtained using low linear energy transfer, “*LET*”, radiations, which indicates that at least two electrons

Download English Version:

<https://daneshyari.com/en/article/9953947>

Download Persian Version:

<https://daneshyari.com/article/9953947>

[Daneshyari.com](https://daneshyari.com)